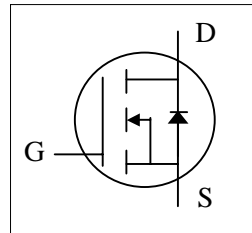




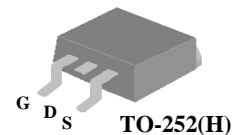
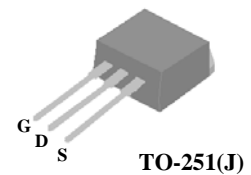
- ▼ 100% Avalanche Test
- ▼ Fast Switching Characteristics
- ▼ Simple Drive Requirement
- ▼ RoHS Compliant & Halogen-Free



| | |
|--------------|------------|
| BV_{DSS} | 600V |
| $R_{DS(ON)}$ | 5 Ω |
| I_D | 2A |

Description

AP4002 series are specially designed as chopper regulator, DC/DC converter and power drive application. The APEC MOSFET provide the best combination of fast switching, ruggedized design and cost-effectiveness.



Absolute Maximum Ratings

| Symbol | Parameter | Rating | Units |
|--------------------------|--|------------|---------------|
| V_{DS} | Drain-Source Voltage | 600 | V |
| V_{GS} | Gate-Source Voltage | ± 30 | V |
| $I_D @ T_C = 25^\circ C$ | Continuous Drain Current, $V_{GS} @ 10V$ | 2 | A |
| I_{DM} | Pulsed Drain Current ¹ | 8 | A |
| $P_D @ T_C = 25^\circ C$ | Total Power Dissipation | 20 | W |
| | Linear Derating Factor | 0.16 | W/ $^\circ C$ |
| E_{AS} | Single Pulse Avalanche Energy ² | 20 | mJ |
| I_{AR} | Avalanche Current | 2 | A |
| T_{STG} | Storage Temperature Range | -55 to 150 | $^\circ C$ |
| T_J | Operating Junction Temperature Range | -55 to 150 | $^\circ C$ |

Thermal Data

| Symbol | Parameter | Value | Unit |
|--------|---|-------|--------------|
| Rthj-c | Maximum Thermal Resistance, Junction-case | 6.25 | $^\circ C/W$ |
| Rthj-a | Maximum Thermal Resistance, Junction-ambient (PCB mount) ⁴ | 62.5 | $^\circ C/W$ |
| Rthj-a | Maximum Thermal Resistance, Junction-ambient | 110 | $^\circ C/W$ |



Electrical Characteristics @ $T_j=25^{\circ}\text{C}$ (unless otherwise specified)

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Units |
|--------------|--|-------------------------------|------|------|---------|----------|
| BV_{DSS} | Drain-Source Breakdown Voltage | $V_{GS}=0V, I_D=250\mu A$ | 600 | - | - | V |
| $R_{DS(ON)}$ | Static Drain-Source On-Resistance ³ | $V_{GS}=10V, I_D=1A$ | - | - | 5 | Ω |
| $V_{GS(th)}$ | Gate Threshold Voltage | $V_{DS}=V_{GS}, I_D=250\mu A$ | 2 | - | 4 | V |
| g_{fs} | Forward Transconductance | $V_{DS}=10V, I_D=2A$ | - | 1.5 | - | S |
| I_{DSS} | Drain-Source Leakage Current | $V_{DS}=600V, V_{GS}=0V$ | - | - | 100 | μA |
| I_{GSS} | Gate-Source Leakage | $V_{GS}=\pm 30V, V_{DS}=0V$ | - | - | ± 1 | μA |
| Q_g | Total Gate Charge ³ | $I_D=2A$ | - | 12 | 19 | nC |
| Q_{gs} | Gate-Source Charge | $V_{DS}=480V$ | - | 2 | - | nC |
| Q_{gd} | Gate-Drain ("Miller") Charge | $V_{GS}=10V$ | - | 5.5 | - | nC |
| $t_{d(on)}$ | Turn-on Delay Time ³ | $V_{DD}=200V$ | - | 10 | - | ns |
| t_r | Rise Time | $I_D=1A$ | - | 12 | - | ns |
| $t_{d(off)}$ | Turn-off Delay Time | $R_G=50\Omega, V_{GS}=10V$ | - | 52 | - | ns |
| t_f | Fall Time | $R_D=200\Omega$ | - | 19 | - | ns |
| C_{iss} | Input Capacitance | $V_{GS}=0V$ | - | 375 | 600 | pF |
| C_{oss} | Output Capacitance | $V_{DS}=10V$ | - | 170 | - | pF |
| C_{riss} | Reverse Transfer Capacitance | $f=1.0\text{MHz}$ | - | 45 | - | pF |

Source-Drain Diode

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Units |
|----------|------------------------------------|---|------|------|------|---------|
| V_{SD} | Forward On Voltage ³ | $T_j=25^{\circ}\text{C}, I_S=2A, V_{GS}=0V$ | - | - | 1.5 | V |
| t_{rr} | Reverse Recovery Time ³ | $I_S=2A, V_{GS}=0V,$ | - | 340 | - | ns |
| Q_{rr} | Reverse Recovery Charge | $di/dt=100A/\mu s$ | - | 2.2 | - | μC |

Notes:

1. Pulse width limited by Max. junction temperature.
2. Starting $T_j=25^{\circ}\text{C}, V_{DD}=50V, L=10\text{mH}, R_G=25\Omega$
3. Pulse test
4. Surface mounted on 1 in² copper pad of FR4 board

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

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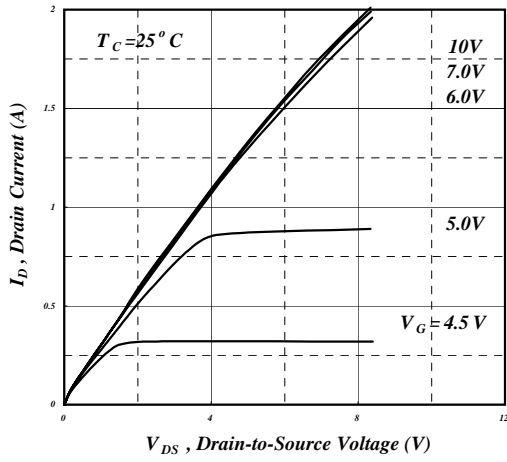


Fig 1. Typical Output Characteristics

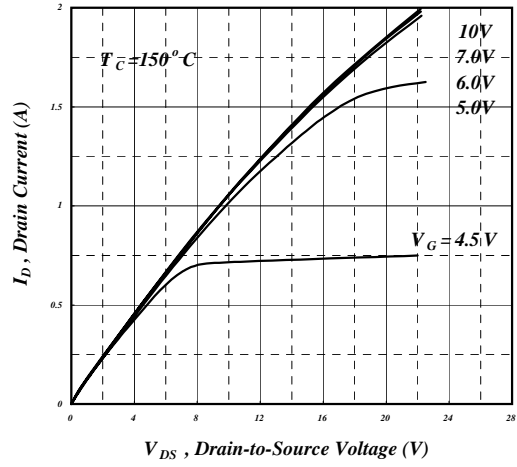


Fig 2. Typical Output Characteristics

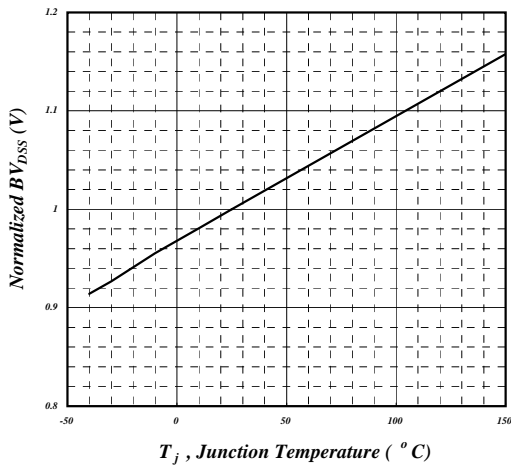


Fig 3. Normalized BV_{DSS} v.s. Junction Temperature

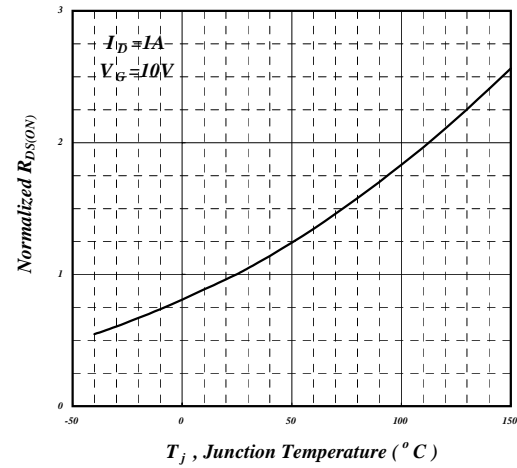


Fig 4. Normalized On-Resistance v.s. Junction Temperature

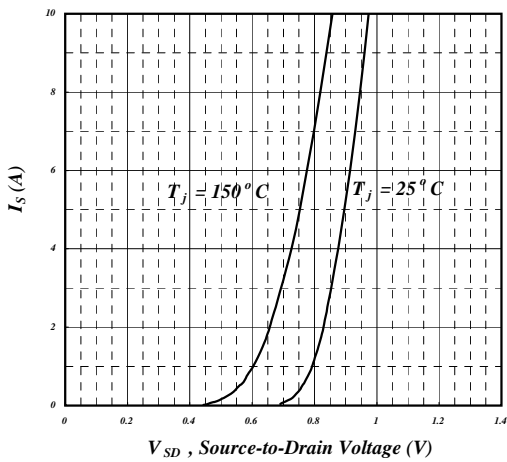


Fig 5. Forward Characteristic of Reverse Diode

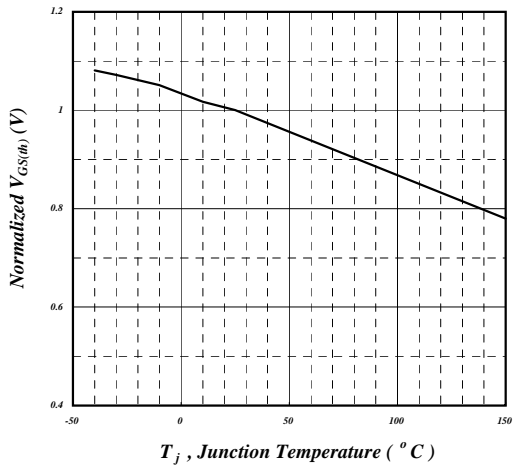


Fig 6. Gate Threshold Voltage v.s. Junction Temperature

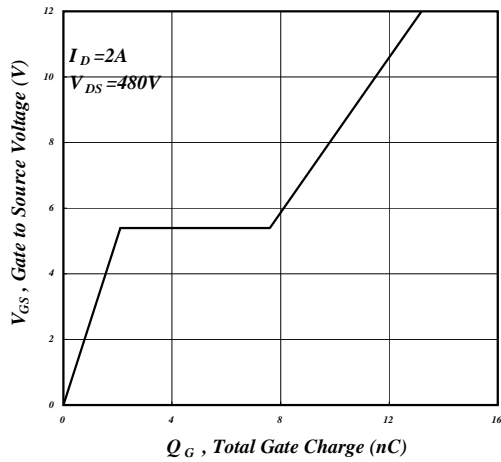


Fig 7. Gate Charge Characteristics

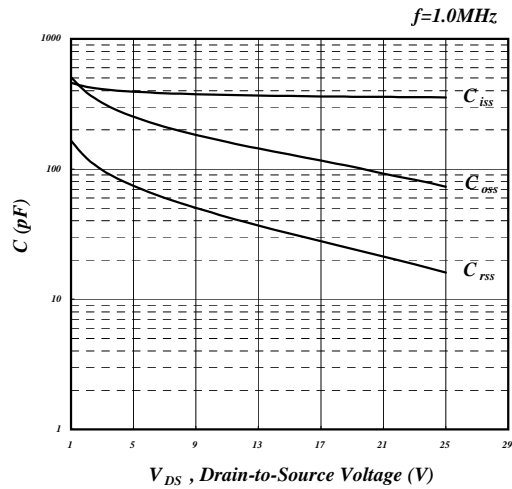


Fig 8. Typical Capacitance Characteristics

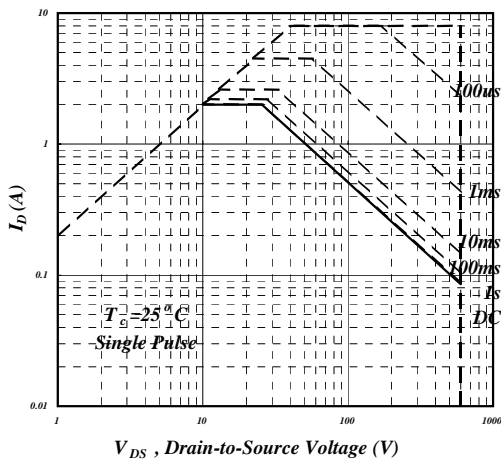


Fig 9. Maximum Safe Operating Area

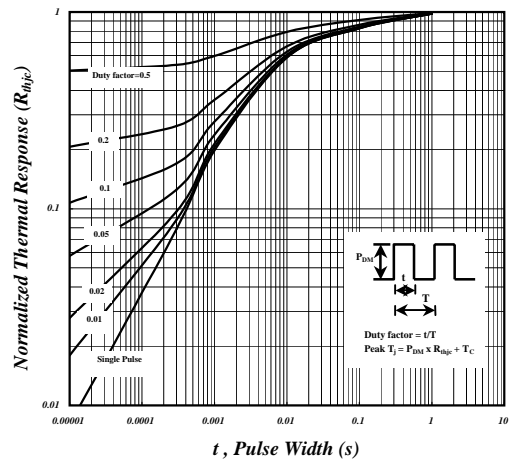


Fig 10. Effective Transient Thermal Impedance

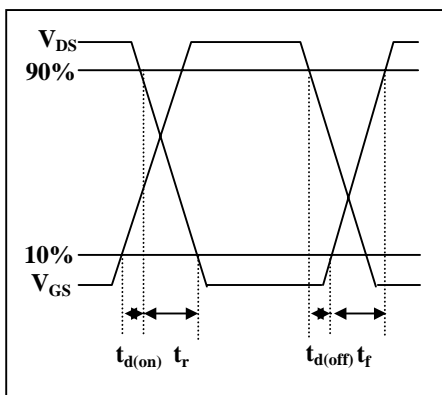


Fig 11. Switching Time Waveform

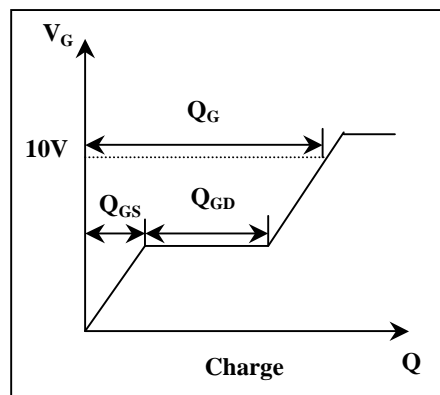


Fig 12. Gate Charge Waveform